Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/770,112	MOUTIN, JEAN-MICHEL	
Examiner	Art Unit	
Allen Wong	2621	

SEARCHED					
Class	Subclass	Date	Examiner		
375	240	1/4/2007	AW		
375	240.01	1/4/2007	AW		
375	240.12	1/4/2007	AW		
375	240.24	1/4/2007	AW		
375	240.28	1/4/2007	AW		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
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